

# FSBM30SM60A

# SPM™ (Smart Power Module)

### **General Description**

FSBM30SM60A is an advanced smart power module (SPM) that Fairchild has newly developed and designed to provide very compact and high performance ac motor drives mainly targeting medium speed low-power inverterdriven application like air conditioners. It combines optimized circuit protection and drive matched to low-loss IGBTs. Highly effective short-circuit current detection/ protection is realized through the use of advanced current sensing IGBT chips that allow continuous monitoring of the IGBTs current. System reliability is further enhanced by the integrated under-voltage lock-out protection. The high speed built-in HVIC provides opto-coupler-less IGBT gate driving capability that further reduce the overall size of the inverter system design. In addition the incorporated HVIC facilitates the use of single-supply drive topology enabling the FSBM30SM60A to be driven by only one drive supply voltage without negative bias. Inverter current sensing application can be achieved due to the divided negative dc terminals.

### **Features**

- UL Certified No. E209204
- 600V-30A 3-phase IGBT inverter bridge including control ICs for gate driving and protection
- Divided negative dc-link terminals for inverter current sensing applications
- · Single-grounded power supply due to built-in HVIC
- Typical switching frequency of 5kHz
- Inverter power rating of 2.4kW / 100~253 Vac
- Isolation rating of 2500Vrms/min.
- Very low leakage current due to using ceramic substrate
- Adjustable current protection level by varying series resistor value with sense-IGBTs

## **Applications**

- AC 100V ~ 253V 3-phase inverter drive for small power (2.4kW) ac motor drives
- Home appliances applications requiring medium switching frequency operation like air conditioners drive system
- Application ratings:
  - Power: 2.4kW / 100~253 Vac
  - Switching frequency : Typical 5kHz (PWM Control)
  - 100% load current : 11A (Irms)
  - 150% load current : 16.5A (Irms) for 1 minute

### **External View**

**Top View** 



**Bottom View** 



Fig. 1.

©2003 Fairchild Semiconductor Corporation Rev. E, August 2003

# **Integrated Power Functions**

• 600V-30A IGBT inverter for 3-phase DC/AC power conversion (Please refer to Fig. 3)

## **Integrated Drive, Protection and System Control Functions**

- - Note) Available bootstrap circuit example is given in Figs. 13 and 14.
- For inverter low-side IGBTs: Gate drive circuit, Short-Circuit (SC) protection
   Control supply circuit under-voltage (UV) protection
- · Fault signaling: Corresponding to a SC fault (Low-side IGBTs) or a UV fault (Low-side control supply circuit)
- Input interface: 5V CMOS/LSTTL compatible, Schmitt trigger input

## **Pin Configuration**

### **Top View**

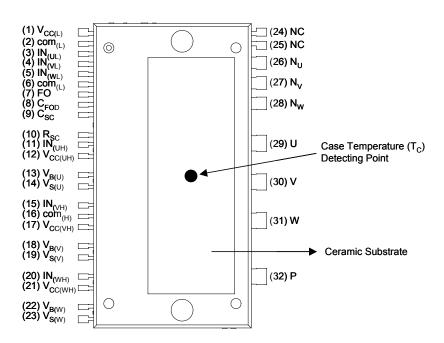


Fig. 2.

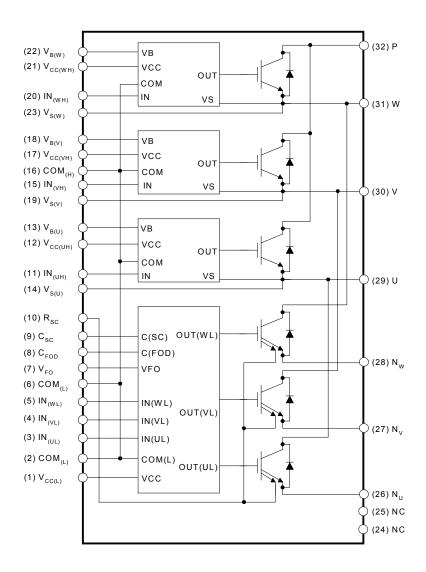
©2003 Fairchild Semiconductor Corporation Rev. E, August 2003

# **Pin Descriptions**

Pin Number	Pin Name	Pin Description
1	$V_{CC(L)}$	Low-side Common Bias Voltage for IC and IGBTs Driving
2	COM <sub>(L)</sub>	Low-side Common Supply Ground
3	IN <sub>(UL)</sub>	Signal Input for Low-side U Phase
4	IN <sub>(VL)</sub>	Signal Input for Low-side V Phase
5	$IN_{(WL)}$	Signal Input for Low-side W Phase
6	$COM_{(L)}$	Low-side Common Supply Ground
7	$V_{FO}$	Fault Output
8	$C_FOD$	Capacitor for Fault Output Duration Time Selection
9	C <sub>SC</sub>	Capacitor (Low-pass Filter) for Short-Circuit Current Detection Input
10	R <sub>SC</sub>	Resistor for Short-Circuit Current Detection
11	IN <sub>(UH)</sub>	Signal Input for High-side U Phase
12	V <sub>CC(UH)</sub>	High-side Bias Voltage for U Phase IC
13	V <sub>B(U)</sub>	High-side Bias Voltage for U Phase IGBT Driving
14	V <sub>S(U)</sub>	High-side Bias Voltage Ground for U Phase IGBT Driving
15	IN <sub>(VH)</sub>	Signal Input for High-side V Phase
16	COM <sub>(H)</sub>	High-side Common Supply Ground
17	V <sub>CC(VH)</sub>	High-side Bias Voltage for V Phase IC
18	V <sub>B(V)</sub>	High-side Bias Voltage for V Phase IGBT Driving
19	V <sub>S(V)</sub>	High-side Bias Voltage Ground for V Phase IGBT Driving
20	IN <sub>(WH)</sub>	Signal Input for High-side W Phase
21	V <sub>CC(WH)</sub>	High-side Bias Voltage for W Phase IC
22	V <sub>B(W)</sub>	High-side Bias Voltage for W Phase IGBT Driving
23	V <sub>S(W)</sub>	High-side Bias Voltage Ground for W Phase IGBT Driving
24	NC	No Connection
25	NC	No Connection
26	N <sub>U</sub>	Negative DC-Link Input for U Phase
27	N <sub>V</sub>	Negative DC–Link Input for V Phase
28	N <sub>W</sub>	Negative DC–Link Input for W Phase
29	U	Output for U Phase
30	V	Output for V Phase
31	W	Output for W Phase
32	Р	Positive DC–Link Input

# Internal Equivalent Circuit and Input/Output Pins

### **Bottom View**



- 1) Inverter low-side is composed of three sense-IGBTs including freewheeling diodes for each IGBT and one control IC which has gate driving, current sensing and protection functions.

  2) Inverter power side is composed of four inverter dc-link input pins and three inverter output pins.

  3) Inverter high-side is composed of three normal-IGBTs including freewheeling diodes and three drive ICs for each IGBT.

Fig. 3.

# **Absolute Maximum Ratings** $(T_J = 25^{\circ}C, Unless Otherwise Specified)$

## **Inverter Part**

Item	Symbol	Condition	Rating	Unit
Supply Voltage	$V_{PN}$	Applied between P- $N_U$ , $N_V$ , $N_W$	450	V
Supply Voltage (Surge)	V <sub>PN(Surge)</sub>	Applied between P- N <sub>U</sub> , N <sub>V</sub> , N <sub>W</sub>	500	V
Collector-Emitter Voltage	V <sub>CES</sub>		600	V
Each IGBT Collector Current	± I <sub>C</sub>	T <sub>C</sub> = 25°C	30	Α
Each IGBT Collector Current	± I <sub>C</sub>	T <sub>C</sub> = 100°C	16	Α
Each IGBT Collector Current (Peak)	± I <sub>CP</sub>	T <sub>C</sub> = 25°C, Instantaneous Value (Pulse)	60	А
Collector Dissipation	P <sub>C</sub>	T <sub>C</sub> = 25°C per One Chip	62	W
Operating Junction Temperature	TJ	(Note 1)	-20 ~ 125	°C

## **Control Part**

Item	Symbol	Condition	Rating	Unit
Control Supply Voltage	V <sub>CC</sub>	Applied between $V_{CC(UH)}$ , $V_{CC(VH)}$ , $V_{CC(WH)}$ - $COM_{(H)}$ , $V_{CC(L)}$ - $COM_{(L)}$	20	V
High-side Control Bias Voltage	V <sub>BS</sub>	Applied between $V_{B(U)}$ - $V_{S(U)}$ , $V_{B(V)}$ - $V_{S(V)}$ , $V_{B(W)}$ - $V_{S(W)}$	20	V
Input Signal Voltage	V <sub>IN</sub>	Applied between $IN_{(UH)}$ , $IN_{(VH)}$ , $IN_{(WH)}$ - $COM_{(H)}$ $IN_{(UL)}$ , $IN_{(VL)}$ , $IN_{(WL)}$ - $COM_{(L)}$	-0.3 ~ V <sub>CC</sub> +0.3	V
Fault Output Supply Voltage	$V_{FO}$	Applied between V <sub>FO</sub> - COM <sub>(L)</sub>	-0.3 ~ V <sub>CC</sub> +0.3	V
Fault Output Current	I <sub>FO</sub>	Sink Current at V <sub>FO</sub> Pin	5	mA
Current Sensing Input Voltage	V <sub>SC</sub>	Applied between C <sub>SC</sub> - COM <sub>(L)</sub>	-0.3 ~ V <sub>CC</sub> +0.3	V

## **Total System**

Item	Symbol	Condition	Rating	Unit
Self Protection Supply Voltage Limit (Short-Circuit Protection Capability)	V <sub>PN(PROT)</sub>	$V_{CC} = V_{BS} = 13.5 \sim 16.5 V$ T <sub>J</sub> = 25°C, Non-repetitive, less than 6μs	400	V
Module Case Operation Temperature	T <sub>C</sub>	Note Fig.2	-20 ~ 100	°C
Storage Temperature	T <sub>STG</sub>		-20 ~ 125	°C
Isolation Voltage	V <sub>ISO</sub>	60Hz, Sinusoidal, AC 1 minute, Connection Pins to Heat-sink Plate	2500	V <sub>rms</sub>

Rev. E, August 2003 ©2003 Fairchild Semiconductor Corporation

Note:
1. It would be recommended that the average junction temperature should be limited to  $T_J \le 125^{\circ}C$  (@ $T_C \le 100^{\circ}C$ ) in order to guarantee safe operation.

# **Absolute Maximum Ratings**

## **Thermal Resistance**

ltem	Symbol	Condition	Min.	Тур.	Max.	Unit
Junction to Case Thermal Resistance	R <sub>th(j-c)Q</sub>	Each IGBT under Inverter Operating Condition	-	-	2.0	°C/W
	R <sub>th(j-c)F</sub>	Each FWDi under Inverter Operating Condition	-	-	3.2	°C/W
Contact Thermal Resistance	R <sub>th(c-f)</sub>	Ceramic Substrate (per 1 Module) Thermal Grease Applied (Note 3)	-	1	0.06	°C/W

- $\label{eq:Note:2} \textbf{Note:} \\ 2. \ \ \text{For the measurement point of case temperature}(T_C), \ please \ refer to \ Fig. \ 2. \\ 3. \ \ The \ thickness \ of \ thermal \ grease \ should \ not \ be \ more \ than \ 100 um. \\ \end{cases}$

# $\textbf{Electrical Characteristics} \quad (T_{j} = 25^{\circ}\text{C, Unless Otherwise Specified})$

## **Inverter Part**

Item	Symbol	Condition	Condition		Тур.	Max.	Unit
Collector - Emitter Saturation Voltage	V <sub>CE(SAT)</sub>	$V_{CC} = V_{BS} = 15V$ $V_{IN} = 0V$	$I_C = 30A, T_J = 25^{\circ}C$	-	-	2.3	V
FWDi Forward Voltage	$V_{FM}$	V <sub>IN</sub> = 5V	$I_C = 30A, T_J = 25^{\circ}C$	-	-	2.6	V
Switching Times	t <sub>ON</sub>	$V_{PN}$ = 300V, $V_{CC}$ = $V_{BS}$ = 15V $I_{C}$ = 30A, $T_{J}$ = 25°C		-	0.39	-	us
	t <sub>C(ON)</sub>			-	0.2	-	us
	t <sub>OFF</sub>		$V_{IN} = 5V \leftrightarrow 0V$ , Inductive Load		0.95	-	us
	t <sub>C(OFF)</sub>	(High, Low-side)		-	0.39	-	us
	t <sub>rr</sub>	(Note 4)		-	0.13	-	us
Collector - Emitter Leakage Current	I <sub>CES</sub>	$V_{CE} = V_{CES}$ , $T_{J} = 25$ °C		-	-	250	μА

©2003 Fairchild Semiconductor Corporation Rev. E, August 2003

 <sup>4.</sup> t<sub>ON</sub> and t<sub>OFF</sub> include the propagation delay time of the internal drive IC. t<sub>C(ON)</sub> and t<sub>C(OFF)</sub> are the switching time of IGBT itself under the given gate driving condition internally. For the detailed information, please see Fig. 4.

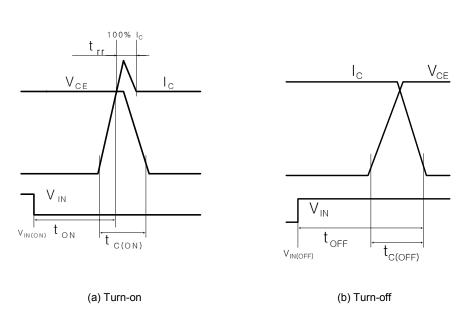


Fig. 4. Switching Time Definition

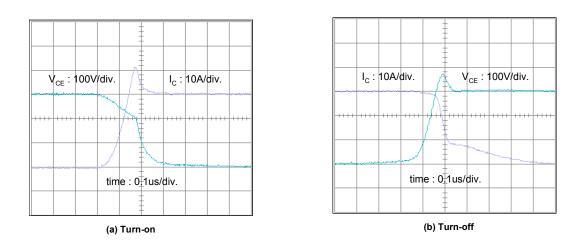


Fig. 5. Experimental Results of Switching Waveforms Test Condition: Vdc=300V, Vcc=15V, L=500uH (Inductive Load),  $T_J$ =25°C

# $\textbf{Electrical Characteristics} \quad (T_J = 25^{\circ}\text{C, Unless Otherwise Specified})$ **Control Part**

Item	Symbol	Condition			Тур.	Max.	Unit
Quiescent V <sub>CC</sub> Supply Cur-	I <sub>QCCL</sub>	V <sub>CC</sub> = 15V	V <sub>CC(L)</sub> - COM <sub>(L)</sub>	-	-	26	mA
rent		$IN_{(UL, VL, WL)} = 5V$					
	I <sub>QCCH</sub>	V <sub>CC</sub> = 15V	V <sub>CC(UH)</sub> , V <sub>CC(VH)</sub> , V <sub>CC(WH)</sub> -	-	-	130	uA
		IN <sub>(UH, VH, WH)</sub> = 5V	COM <sub>(H)</sub>				
Quiescent V <sub>BS</sub> Supply Cur-	$I_{QBS}$	V <sub>BS</sub> = 15V	$V_{B(U)} - V_{S(U)}, V_{B(V)} - V_{S(V)},$	-	-	420	uA
rent		IN <sub>(UH, VH, WH)</sub> = 5V					
Fault Output Voltage	$V_{FOH}$	$V_{SC}$ = 0V, $V_{FO}$ Circuit	: 4.7kΩ to 5V Pull-up	4.5	-	-	V
	$V_{FOL}$	$V_{SC}$ = 1V, $V_{FO}$ Circuit	: 4.7kΩ to 5V Pull-up	-	-	1.1	V
Short-Circuit Trip Level	V <sub>SC(ref)</sub>	V <sub>CC</sub> = 15V (Note 5)			0.51	0.56	V
Sensing Voltage	$V_{SEN}$	$R_{SC} = 56 \Omega$ , $R_{SU} = R_{SV} = R_{SW} = 0 \Omega$ and $I_C = 45A$			0.51	0.56	V
of IGBT Current		(Note Fig. 6)					
Supply Circuit Under-	UV <sub>CCD</sub>	Detection Level		11.5	12	12.5	V
Voltage Protection	UV <sub>CCR</sub>	Reset Level		12	12.5	13	V
	UV <sub>BSD</sub>	Detection Level		7.3	9.0	10.8	V
	UV <sub>BSR</sub>	Reset Level		8.6	10.3	12	V
FaultOutput Pulse Width	t <sub>FOD</sub>	C <sub>FOD</sub> = 33nF (Note 6)		1.4	1.8	2.0	ms
ON Threshold Voltage	V <sub>IN(ON)</sub>	High-Side	Applied between IN <sub>(UH)</sub> , IN <sub>(VH)</sub> ,	-	-	0.8	V
OFF Threshold Voltage	V <sub>IN(OFF)</sub>		IN <sub>(WH)</sub> - COM <sub>(H)</sub>	3.0	-	-	V
ON Threshold Voltage	V <sub>IN(ON)</sub>	Low-Side	Applied between IN <sub>(UL)</sub> , IN <sub>(VL)</sub> ,	-	-	0.8	V
OFF Threshold Voltage	V <sub>IN(OFF)</sub>		IN <sub>(WL)</sub> - COM <sub>(L)</sub>	3.0	-	-	V

# **Recommended Operating Conditions**

lt a ma	Cumbal	Condition	Values			11
Item	Symbol	Condition		Тур.	Max.	Unit
Supply Voltage	$V_{PN}$	Applied between P - N <sub>U</sub> , N <sub>V</sub> , N <sub>W</sub>	-	300	400	V
Control Supply Voltage	V <sub>CC</sub>	Applied between $V_{CC(UH)}$ , $V_{CC(VH)}$ , $V_{CC(WH)}$ - $COM_{(H)}$ , $V_{CC(L)}$ - $COM_{(L)}$	13.5	15	16.5	V
High-side Bias Voltage	$V_{BS}$	Applied between $V_{B(U)}$ - $V_{S(U)}$ , $V_{B(V)}$ - $V_{S(V)}$ , $V_{B(W)}$ - $V_{S(W)}$	13.5	15	16.5	V
Blanking Time for Preventing Arm-short	t <sub>dead</sub>	For Each Input Signal	3	-	-	us
PWM Input Signal	$f_{PWM}$	$T_{C} \le 100^{\circ}C, T_{J} \le 125^{\circ}C$	-	5	-	kHz
Input ON Threshold Voltage	$V_{IN(ON)}$	Applied between IN <sub>(UH)</sub> , IN <sub>(VH)</sub> , IN <sub>(WH)</sub> - COM <sub>(H)</sub> , IN <sub>(UL)</sub> , IN <sub>(VL)</sub> , IN <sub>(WL)</sub> - COM <sub>(L)</sub>		0 ~ 0.65	5	V
Input OFF Threshold Voltage	V <sub>IN(OFF)</sub>	$ \begin{array}{c} \text{Applied between IN}_{(\text{UH})},  \text{IN}_{(\text{VH})},  \text{IN}_{(\text{WH})} - \\ \text{COM}_{(\text{H})},  \text{IN}_{(\text{UL})},  \text{IN}_{(\text{VL})},  \text{IN}_{(\text{WL})} -  \text{COM}_{(\text{L})} \end{array} $		4 ~ 5.5		V

Note:

5. Short-circuit current protection is functioning only at the low-sides. It would be recommended that the value of the external sensing resistor ( $R_{SC}$ ) should be selected around 56  $\Omega$  in order to make the SC trip-level of about 45A at the shunt resistors ( $R_{SU}$ , $R_{SV}$ , $R_{SW}$ ) of  $\Omega\Omega$ . For the detailed information about the relationship between the external sensing resistor ( $R_{SC}$ ) and the shunt resistors ( $R_{SU}$ , $R_{SV}$ , $R_{SW}$ ), please see Fig. 6.

6. The fault-out pulse width  $t_{FOD}$  depends on the capacitance value of  $C_{FOD}$  according to the following approximate equation:  $C_{FOD} = 18.3 \times 10^{-6} \times t_{FOD}[F]$ 

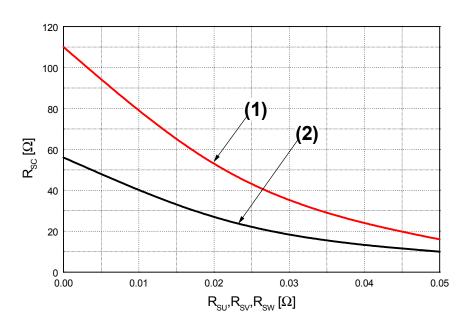


Fig. 6. R<sub>SC</sub> Variation by change of Shunt Resistors (R<sub>SU</sub>, R<sub>SV</sub>, R<sub>SW</sub>) for Short-Circuit Protection (1) @ around 100% Rated Current Trip (I<sub>C</sub> = .30A) (2) @ around 150% Rated Current Trip (I<sub>C</sub> = .45A)

# **Mechanical Characteristics and Ratings**

ltom		Condition			Limits			
Item		Condition	Min.	Тур.	Max.	Unit		
Mounting Torque	Mounting Screw: M4	Recommended 10Kg•cm	8	10	12	Kg•cm		
	(Note 7 and 8)	Recommended 0.98N•m	0.78	0.98	1.17	N•m		
Ceramic Flatness		Note Fig.7	0	_	+120	um		
Weight			-	35	-	g		

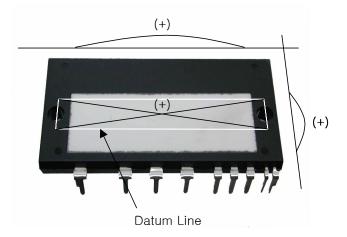


Fig. 7. Flatness Measurement Position of The Ceramic Substrate

- Note:
  7. Do not make over torque or mounting screws. Much mounting torque may cause ceramic cracks and bolts and Al heat-fin destruction.
  8. Avoid one side tightening stress. Fig.8 shows the recommended torque order for mounting screws. Uneven mounting can cause the SPM ceramic substrate to be damaged.

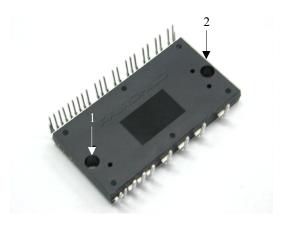
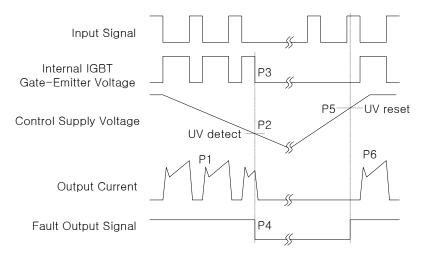


Fig. 8. Mounting Screws Torque Order

©2003 Fairchild Semiconductor Corporation Rev. E, August 2003

## **Time Charts of SPMs Protective Function**

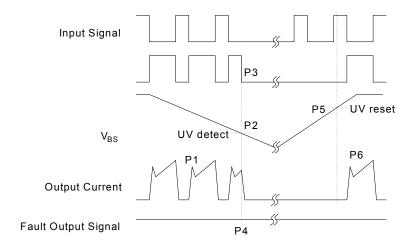


P1: Normal operation - IGBT ON and conducting current

P2 : Under-Voltage detection P3 : IGBT gate interrupt P4 : Fault signal generation P5 : Under-Voltage reset

P6: Normal operation - IGBT ON and conducting current

Fig. 9. Under-Voltage Protection (Low-side)



P1: Normal operation - IGBT ON and conducting current

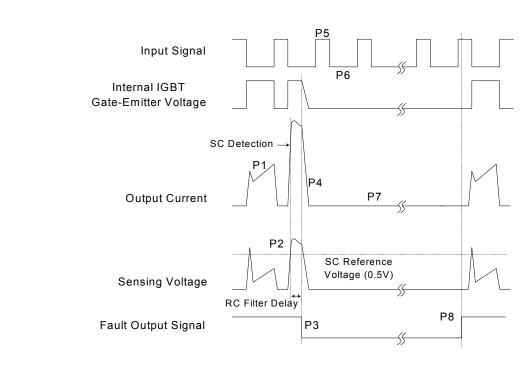
P2 : Under-Voltage detection P3 : IGBT gate interrupt

P4 : No fault signal P5 : Under-Voltage reset

P6: Normal operation - IGBT ON and conducting current

Fig. 10. Under-Voltage Protection (High-side)

©2003 Fairchild Semiconductor Corporation Rev. E, August 2003



P1: Normal operation - IGBT ON and conducting current

P2 : Short-Circuit current detection

P3: IGBT gate interrupt / Fault signal generation

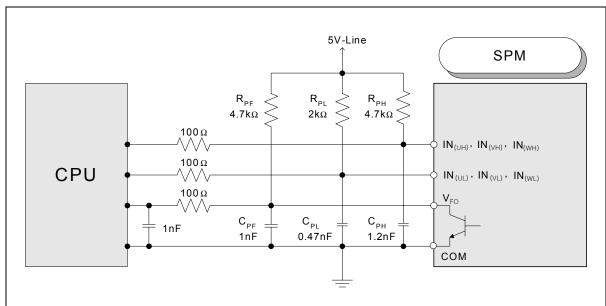
P4: IGBT is slowly turned off

P5 : IGBT OFF signal
P6 : IGBT ON signal - but IGBT cannot be turned on during the fault Output activation

P7 : IGBT OFF state

P8: Fault Output reset and normal operation start

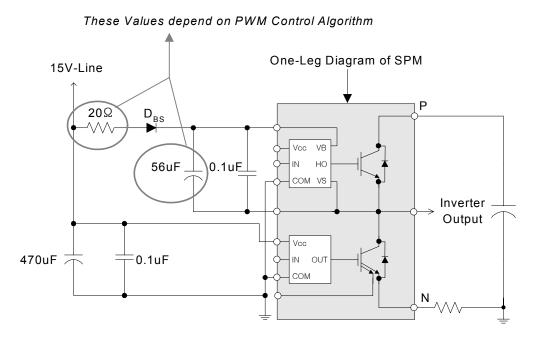
Fig. 11. Short-Circuit Current Protection (Low-side Operation only)



### Note:

- 1) It would be recommended that by-pass capacitors for the gating input signals, IN<sub>(UL)</sub>, IN<sub>(UL)</sub>, IN<sub>(UL)</sub>, IN<sub>(UH)</sub>, IN<sub>(UH)</sub>, IN<sub>(UH)</sub>, and IN<sub>(WH)</sub> should be placed on the SPM pins and on the both sides of CPU and SPM for the fault output signal, V<sub>FO</sub>, as close as possible.
   2) The logic input is compatible with standard CMOS or LSTTL outputs.
- 2) The Region in the second and the second of the second o

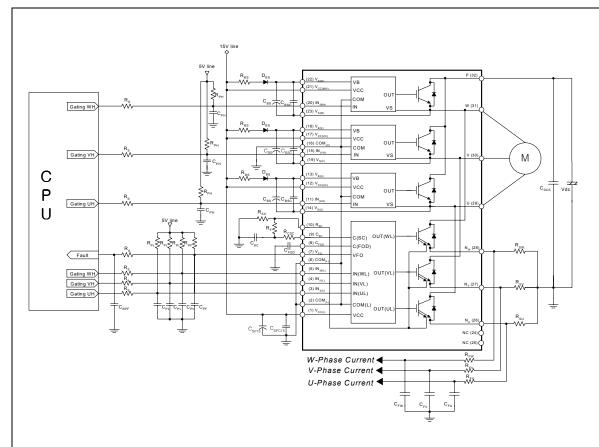
Fig. 12. Recommended CPU I/O Interface Circuit



It would be recommended that the bootstrap diode, D<sub>BS</sub>, has soft and fast recovery characteristics.

Fig. 13. Recommended Bootstrap Operation Circuit and Parameters

©2003 Fairchild Semiconductor Corporation Rev. E, August 2003



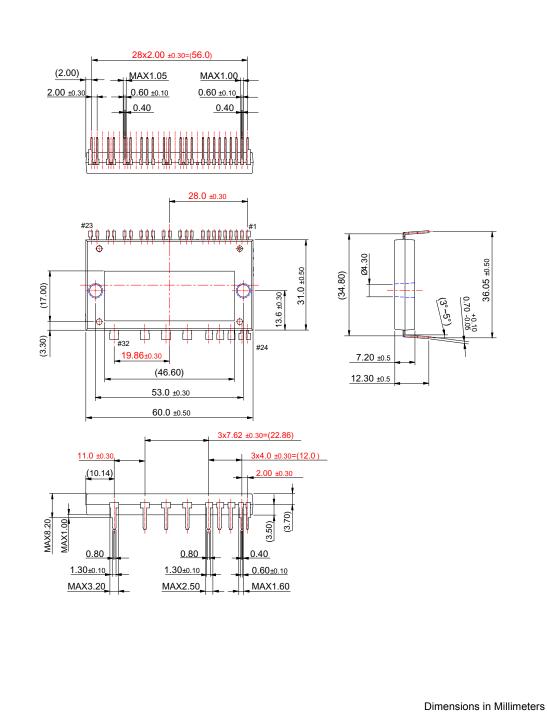
- 1) R<sub>PL</sub>C<sub>PL</sub>/R<sub>PH</sub>C<sub>PH</sub> /R<sub>PF</sub>C<sub>PF</sub> coupling at each SPM input is recommended in order to prevent input signals' oscillation and it should be as close as possible to each SPM input oin.
- 2) By virtue of integrating an application specific type HVIC inside the SPM, direct coupling to CPU terminals without any opto-coupler or transformer isolation is
- $V_{FO}$  output is open collector type. This signal line should be pulled up to the positive side of the 5V power supply with approximately  $4.7 \text{k}\Omega$  resistance. Please refer to Fig. 14.
- C<sub>SP15</sub> of around 7 times larger than bootstrap capacitor C<sub>BS</sub> is recommended.
- 5)  $V_{FO}$  output pulse width should be determined by connecting an external capacitor( $C_{FOD}$ ) between  $C_{FOD}$ (pin8) and  $COM_{(L)}$ (pin2). (Example : if  $C_{FOD}$  = 33 nF, then t<sub>FO</sub> = 1.8 ms (typ.)) Please refer to the note 6 for calculation method.
- 6) Each input signal line should be pulled up to the 5V power supply with approximately 4.7kΩ (at high side input) or 2kΩ (at low side input) resistance (other RC coupling circuits at each input may be needed depending on the PWM control scheme used and on the wiring impedance of the system's printed circuit board). Approximately a 0.22~2nF by-pass capacitor should be used across each power supply connection terminals.

- To prevent errors of the protection function, the wiring around R<sub>SC</sub>, R<sub>F</sub> and C<sub>SC</sub> should be as short as possible.
   In the short-circuit protection circuit, please select the R<sub>F</sub>C<sub>SC</sub> time constant in the range 3~4 μs.
   To enhance the noise immunity, C<sub>SC</sub> pin should be connected to the external circuit through a series resistor, R<sub>CSC</sub>, which is approximately 390Ω. R<sub>SCS</sub> should be connected to  $C_{\mbox{\footnotesize SC}}$  pin as close as possible.
- 10)Each capacitor should be mounted as close to the pins of the SPM as possible.
- 11)To prevent surge destruction, the wiring between the smoothing capacitor and the P&N pins should be as short as possible. The use of a high frequency non-inductive capacitor of around 0.1~0.22 uF between the P&N pins is recommended.
- 12)Relays are used at almost every systems of electrical equipments of home appliances. In these cases, there should be sufficient distance between the CPU and the relays. It is recommended that the distance be 5cm at least.

Fig. 14. Typical Application Circuit

# **Detailed Package Outline Drawings**

# SPM32-AA



### **TRADEMARKS**

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

FACT Quiet Series™ LittleFET™ ACEx™ Power247™ SuperSOT™-6 MICROCOUPLER™ PowerTrench® ActiveArray™ SuperSOT™-8 FAST® Bottomless™ MicroFET™ **OFET®** SvncFET™ FASTr™ CoolFET™ QSTM TinyLogic<sup>®</sup>  $\mathsf{FRFET}^\mathsf{TM}$ MicroPak™ CROSSVOLT™ MICROWIRE™ QT Optoelectronics™ TINYOPTO™ GlobalOptoisolator™ TruTranslation™ DOME™ GTO™ Quiet Series™ MSX™ UHC™ EcoSPARK™ RapidConfigure™ HiSeC™ MSXPro™ UltraFET® E<sup>2</sup>CMOS<sup>TM</sup> I2CTM  $OCX^{TM}$ RapidConnect™ EnSigna™ SILENT SWITCHER®  $VCX^{TM}$ ImpliedDisconnect<sup>™</sup> OCXPro<sup>™</sup> FACT™ OPTOLOGIC® SMART START™ ISOPLANAR™ SPM™ Across the board. Around the world.™ OPTOPLANAR™ Stealth™ PACMAN™ The Power Franchise™ РОРТМ SuperSOT™-3

### DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS. NOR THE RIGHTS OF OTHERS.

### LIFE SUPPORT POLICY

Programmable Active Droop™

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the

2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

### PRODUCT STATUS DEFINITIONS

### **Definition of Terms**

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.